


<b>Search Notes</b> 	Application No.	Applicant(s)	
	10/018,686	ONISHI ET AL	
	Examiner	Art Unit	
	Michael V Battaglia	2652	

SEARCHED			
Class	Subclass	Date	Examiner
369	112.01	8/16/2004	MB
S	112.29	S	S

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
369	112.01	4/11/2005	MB
	112.29		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
((laser ((light radiation) ad) (source emit\$4))) with (focus focal) with collimat\$3 with (nearer farther further closer)	8/16/2004	MB
((magnif\$7 with cd\$4) same (magnif\$7 with dvd\$4))	8/17/2004	MB
369/\$7.ccls. and ((second different plural\$3) near3 wave\$1length\$1) and (substrate with (different second ("0.6" "1.2")) with	8/16/2004	MB
369(text search only-- see Search History Printout)	11/23/2005	MB
11	5/24/2006	MB